## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination OKAMOTO ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*	:	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0141385	07-2003	Xu, Min	239/463
	В	US-6,205,983	03-2001	Egizi, Lisa Johnenne	123/531
·	С	US-6,170,763	01-2001	Fuchs et al.	239/533.12
•	D	US-2004/0159721	08-2004	Shiraishi et al.	239/533.12
·	Е	US-2004/0129806	07-2004	Dantes et al.	239/533.12
	F	US-2004/0026538	02-2004	Heyse, Jorg	239/533.12
	G	US-2003/0222159	12-2003	Kobayashi et al.	239/533.12
	Н	US-2003/0164412	09-2003	Iwase, Satoru	239/533.12
	ı	US-6,848,635	02-2005	Xu, Min	239/533.12
	J	US-6,929,196	08-2005 ′	Togashi et al.	239/533.14
	К	US-6,695,229	02-2004	Heinbuch et al.	239/494
	L	US-6,257,496	07-2001	Wyant, Gordon	239/5
	М	US-			·.

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z			_		
	0					
	Φ					
	σ					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	٧					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.